

Search Notes

Application/Control No.

10/665,698

Examiner

Alan S. Chen

Applicant(s)/Patent under
Reexamination

XUE, XIN

Art Unit

2182

SEARCHED

Class	Subclass	Date	Examiner
710	52	6/2/2006	ASC
↓	62	↓	↓
↓	65	↓	↓
↓	66	↓	↓
↓	72	↓	↓
709	217-219	↓	↓
707	200	↓	↓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
(EAST) USPAT; USPGPUB; EPO; JPO; IBM_TDB; DERWENT Inventor Search	6/2/2006	ASC
NPL search IP.com IEEE Xplore	6/2/2006	ASC